

**INSPECTION REQUIREMENTS  
ELEVATOR APPARATUS  
SUBSCRIBERS LINK  
GENERAL EQUIPMENT REQUIREMENTS  
PANEL SYSTEMS**

TABLE 815-019-182 ISSUE 1-D

Lot Range			A	B	C	D	E	F	G						
Lot Size (Number of Sender Selector and District)			1	161	501	851	1251	1751	2251						
Lot Size (Finder Elevators in Equipment Group)			160	500	850	1250	1750	2250	3000						
Sample Size* (Elevators)			All	160	180	230	280	380	400						
Inspection Item	Allowable Per Cent Defective For Lot	Basis	Allowable Defect Numbers and Spottiness Numbers												
			SN	AN	SN	AN	SN	AN	SN	AN	SN	AN	SN	AN	
1. Rack Tongue Position	2.0	Rack	-	2	1	1	1	1	2	1	2	1	4	1	4
2. Rack Coupling Pin Engagement	2.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4
3. Stop Collars Loose (Including No. 1-A Guide) (w)	2.0	Collar	-	2	3	2	5	2	5	2	7	2	10	2	11
4. Down Stop Collar Location	2.0	Brush Rod	-	2	1	1	1	1	2	1	2	1	4	1	4
5. Compensator Location	2.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4
6. Bent Multiple Bank Terminals* (w)	0.02	Terminal	-	5	14	4	16	3	21	3	27	3	35	3	39
7. Bearings Loose (w)	2.0	Bearing	-	3	6	3	7	2	9	2	13	2	16	2	18
8. Brush Rod Bearing Gap	3.0	"	-	4	10	3	11	3	15	3	19	3	25	3	28
9. Freedom of Movement of Brush Rod	2.0	Brush Rod	-	2	1	1	1	1	2	1	2	1	4	1	4
10. Securely Mounted and Assembled (w)	1.0	Brush	-	2	1	1	1	1	2	1	2	1	4	1	4
11. Multiple Brush Intrusion	2.0	"	-	2	3	2	4	2	5	2	7	2	10	2	11
12. Multiple Brush Stud Gap	1.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4
13. Parallelism of Brush Springs	3.0	"	-	3	6	3	7	2	9	2	12	2	16	2	18
14. Brush Spring Tension	3.0	"	-	3	6	3	7	2	9	2	12	2	16	2	18
15. Vertical Location of Sleeve Springs of Upper Brush on each Rod	1.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4
16. Vertical Location of Sleeve Springs of Lower Brush on each Rod and Tip and Ring Springs of All Brushes	1.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4
17. No. 1-A Guide Location and Up Stop Collar Location	2.0	Brush Rod	-	2	1	1	1	1	2	1	2	1	4	1	4
18. Smooth Brush Travel	1.0	Brush	-	2	1	1	1	1	2	1	2	1	4	1	4
19. Pawl Engagement	3.0	Rack	-	2	2	2	2	1	4	1	5	1	6	1	7
20. Pawl Clearance (Snagging)	2.0	"	-	2	1	1	1	1	2	1	2	1	4	1	4

AN = Allowable Number of defects in sample.

SN = Spottiness Number (applying to sub-samples).  
Note: The portion of the sample selected from one side of a frame constitutes a sub-sample.

\* The sample shall be selected on the basis of elevators as specified and shall include an equal number of Sender Selector and District Finder Elevators. All of the stop collars, bearings, multiple brushes, compensators, etc., associated with each elevator of the sample shall be

included. The vertical rows of multiple bank terminals opposite the multiple brushes selected shall also be considered a part of the sample.

(w) Requirements for items marked with a "w" are based on accepted standards of workmanship. For requirements for the remaining items refer to Bell System Practices, Section 026-125-701 and Section 026-125-706.

For detailed explanation and use of Table refer to 815-018-180.

Bell Telephone Laboratories, Inc.